### **Proposed Final Pinout for FE Chips**

K. Einsweiler, LBNL

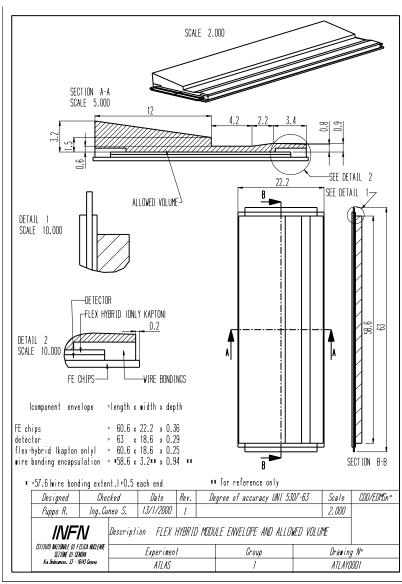
### **Geometry and Pinout issues:**

•Need to match production pinout and geometry to proposed module envelope.

Propose final pinout, satisfying these constraints

### Overview of Module Envelope

## Summarize constraints on module envelope:



#### Constraints on FE die size:

- Present prototypes use: 7.2x(8.0+2.8)mm design size with 0.1mm dicing zone all around: 7.4x11.0mm as-cut die size.
- Production size agreed to be same: Provides total chip envelope in z of 8\*7.4 + 7\*0.2 = 60.6mm

### Constraints on FE bonding region:

- End chips have a constraint on the region which may be wire-bonded, in order to provide good Z overlap. Bonds must fit in central 57.6mm of module, meaning central 4.4mm out of the 7.4mm as-cut die width.
- •If we retain the present 150μ bondpad spacing, that corresponds to 30 bonding pads (4.35mm + pad size).

## Proposed Final FE Chip Pinout (30 bonded pads):

•Total of 10 power pins, positioned at 1/4 and 3/4 points in die (mirror or not ?):

```
p11, p38 VDDA
p12, p37 VCCA
p13, p36 AGnd
p14, p35 DGnd
p15, p34 DVdd
```

Total of 9 Command and Address pins:

```
p16 CCK
p17 DI
p18 LD
p19, p20 STRn, STRp
p21 - p24 GA0 - GA3
```

•Total of 1 analog pin (may become optional if new chopper works very well):

```
p25 VCal
```

Total of 6 control pins:

```
p26, p27 SYNCn, SYNCp
p28, p29 XCKn, XCKp
p30, p31 LV1n, LV1p
```

Total of 2 output pins

```
p32, p33 DOn, DOp
```

Total of 2 detector pins:

```
p10 DGuard
p39 DGrid
```

## To reach this, have removed 18 pads from present pinout:

- RSTb and Shield, and Analog pins (I1-I8, and VCCD/VTH)
- •All monitoring pins (MonHit, MonSel, MonRef, MonAmp)
- Propose to retain most on the die, in locations compatible with present floorplans:
- Total of 1 control pin:

```
p40 RSTb
```

Total of 8 current monitor pins:

p2 l1 p3 l2 p4 l3 p5 l4 p6 l5 p7 l6

p8 l7 p9 l8

• Total of 2 voltage monitor pins and 6 special monitoring pins:

```
p41 VCCD
p42 VTH
p43, p44 MonHitn, MonHitp
p45, p46 MonSeln, MonSelp
p47 MonAmp
p48 MonRef
```

# **Proposed Pad Geometry:**

- •Retain present 100μ x 100μ pad size, with 150μ pitch
- •Continue to locate pads close to the lower die edge, as for demonstrator chips.
- •The present demonstrator geometry has 48 pads, with centers along a line 175µ above the bottom (referenced to the as-cut die size of 7.4x11.0mm). The first pad center is also 175µ from the vertical edge referenced to the as-cut die size.
- Propose that this pad placement would be retained, and only the central 30 pads would be used for production bonding:

```
pp 11
pp 11
pp 11
pp 11
pp 12
pp 14
pp 13
pp 14
pp 13
pp 14
pp 16
pp 17
pp 17
pp 17
pp 18
pp 17
pp 18
pp 17
pp 19
```

